

Silicon N-Channel Junction FET

Description

The 2SK125 is an N-Channel silicon junction type field effect transistor developed for low-noise amplification at frequencies up to UHF. It is especially suitable for when a wide dynamic range is required.

Features

- High power gain
12.5 dB (Typ.)
($f = 100$ MHz Gate grounded)
- Low noise figure
1.5 dB (Typ.)
($f = 100$ MHz Gate grounded)
- Wide dynamic range
3rd intermodulation distortion
-52 dB (Typ.)
($f = 100$ MHz at $100 \text{ dB}\mu$ input)
- Small inverse transfer coefficient
 $|S_{12}| = 0.035$ (Typ.)
($f = 500$ MHz Gate grounded)

Structure

Silicon N-Channel junction FET.

Application

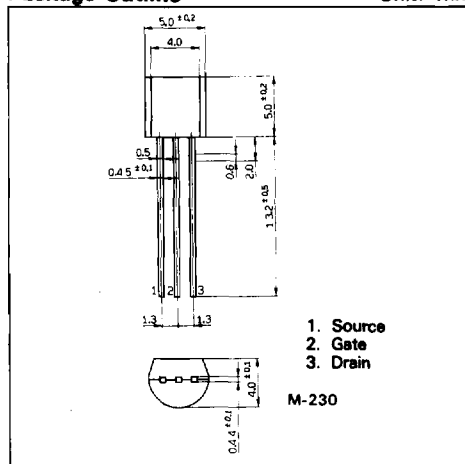
UHF band amplification, mixing, oscillation, analog switches.

Absolute Maximum Ratings ($T_a = 25^\circ\text{C}$)

• Drain to gate voltage	VDGO	35	V
• Source to gate voltage	VSGO	35	V
• Drain current	ID	100	mA
• Gate current	IG	10	mA
• Channel temperature	Tj	120	°C
• Storage temperature	Tstg	-50 to +120	°C
• Allowable power dissipation	PD	300	mW

Package Outline

Unit: mm



Electrical Characteristics

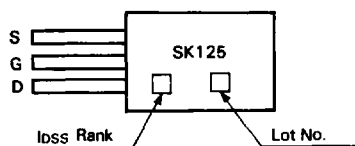
 $T_a = 25^\circ\text{C}$

Item	Symbol	Condition	Min.	Typ.	Max.	Unit
Gate cutoff current	I_{GSS}	$V_{GS} = -15\text{V}, V_{DS} = 0$			-10	nA
Gate to source voltage	V_{GSS}	$I_G = 10\mu\text{A}, V_{DS} = 0$	-35			V
Drain current	I_{DSS}	$V_{DS} = 10\text{V}, V_{GS} = 0$ $P.W = 300\mu\text{s}$	40		75	mA
Gate to source cutoff voltage	$V_{GS(OFF)}$	$V_{DS} = 10\text{V}, I_D = 100\mu\text{A}$	-2		-6	V
Forward transfer conductance	$ Y_{fs} $	$V_{DS} = 10\text{V}, I_D = 10\text{mA}$ $f = 1\text{ kHz}$	10	14		mS
Reverse transfer capacitance	C_{rss}	$V_{DG} = 10\text{V}, I_S = 0\text{mA}$ $f = 1\text{ MHz}, \text{source grounded}$		2.6	3	pF
Power gain	PG	$V_{DG} = 10\text{V}, I_D = 10\text{mA}$ $f = 100\text{ MHz}, BW = 2.8\text{ MHz}$ *1	10	12.5		dB
Noise figure	NF	$V_{DG} = 10\text{V}, I_D = 10\text{mA}$ $f = 100\text{ MHz}, BW = 2.8\text{ MHz}$ At the NF of the amplifier in the next stage is 4.2 dB *1		1.8	2.5	dB
Intermodulation distortion	IMD	$V_{DG} = 10\text{V}, I_D = 10\text{mA}$ $f_1 = 100\text{ MHz}, f_2 = 100.1\text{ MHz}$ at 100 dB μ input *2	-45	-52		dB
Junction to ambient thermal resistance	θ_{j-a}				190	$^\circ\text{C/W}$

Note) *1. See the 100 MHz, PG, NF, test circuit.

*2. See the 100 MHz IMD test circuit.

Mark



Classification

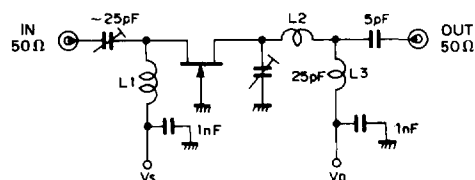
Rank	I_{DSS} (mA) $V_{DS} = 10\text{V}$ $V_{GS} = 0\text{V}$
2	40 to 75
3	40 to 52
4	48 to 63
5	57 to 75

Standard Circuit Design Data

 $T_a = 25^\circ\text{C}$

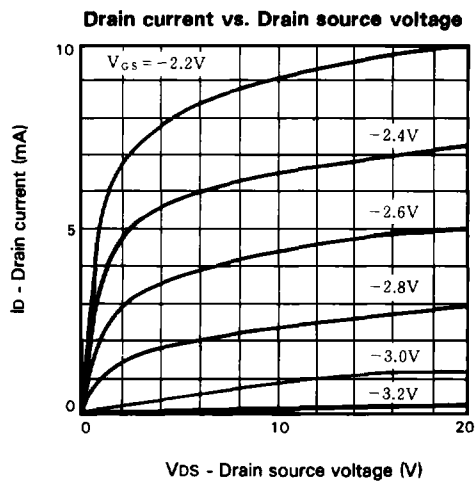
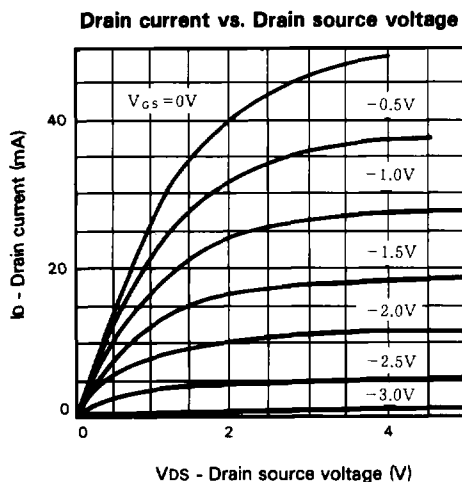
Item	Symbol	Condition	Typ.	Unit
Input resistance	r_{ig}	$V_{DG} = 10\text{V}, I_D = 10\text{mA}$ $f = 100\text{MHz}$	70	Ω
Input capacitance	C_{ig}		3.0	pF
Output resistance	r_{og}		5	k Ω
Output capacitance	C_{og}		3.0	pF
Power gain	PG	$V_{DG} = 10\text{V}, I_D = 10\text{mA}$ $f = 500\text{MHz}, BW = 12\text{MHz}$	7.0	dB
Noise figure	NF		4.0	dB
Reverse transfer coefficient	$ S_{12} $	$V_{DG} = 10\text{V}, I_D = 10\text{mA}$ $f = 500\text{MHz}$	0.035	
Equivalent input noise voltage	$\bar{e}_n$	$V_{DS} = 10\text{V}, I_D = 10\text{mA}$ $f = 1\text{kHz}$	3	nV/ $\sqrt{\text{Hz}}$
Drain source ON resistance	$R_{(ON)}$	$I_D = 10\text{mA}, V_{GS} = 0\text{V}$	35	Ω
Drain cutoff current	$I_{D(OFF)}$	$V_{DS} = 10\text{V}, V_{GS} = -10\text{V}$	0.1	nA

100 MHz PG, NF Test Circuit

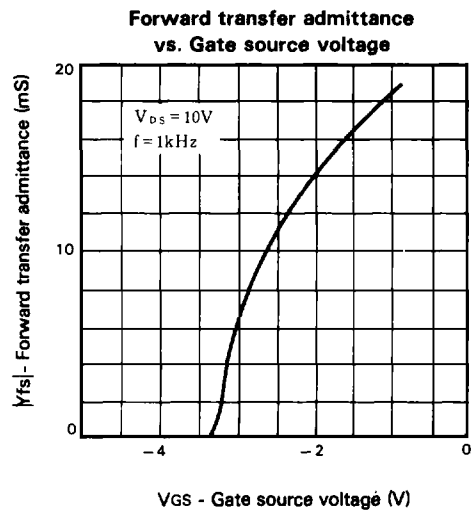
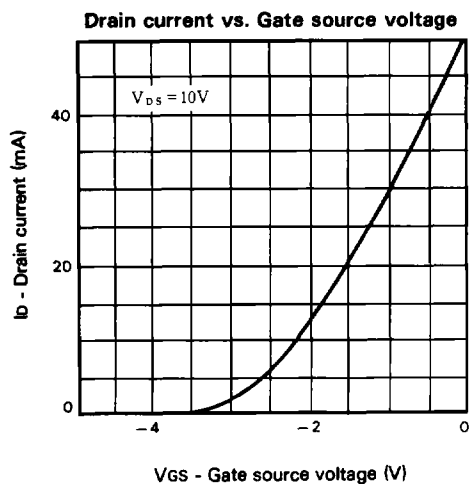


L1 : 0.45 ϕ mm polyurethane wire $\phi 3\text{ mm } 10.5\text{ t}$
 L2, L3 : 0.45 ϕ mm polyurethane wire $\phi 3\text{ mm } 5.5\text{ t}$

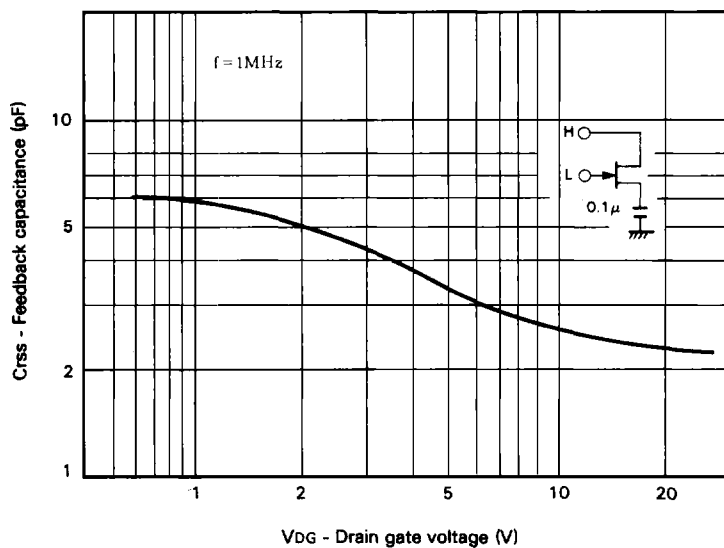
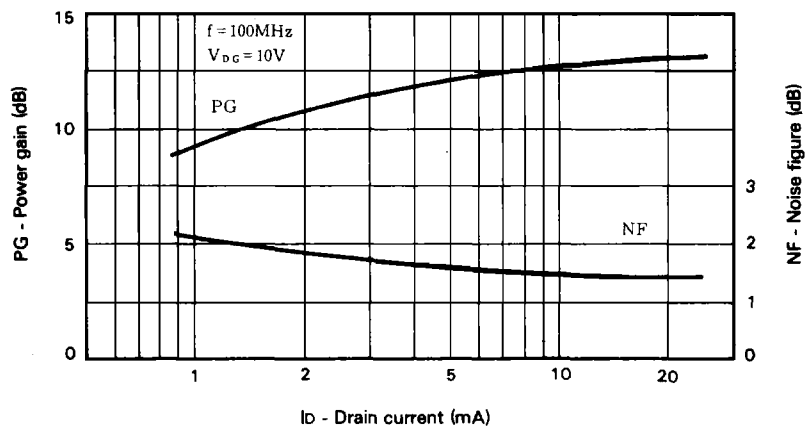
Output Characteristics



Transfer Characteristics

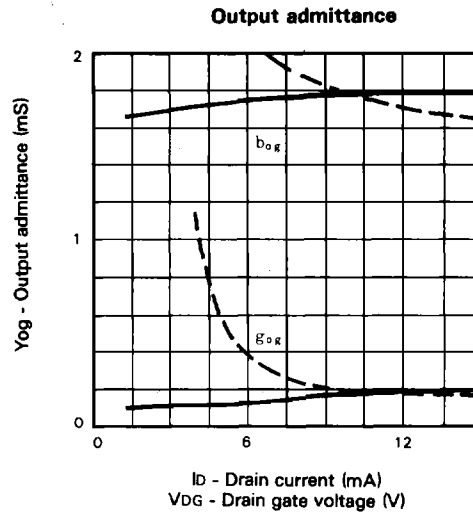
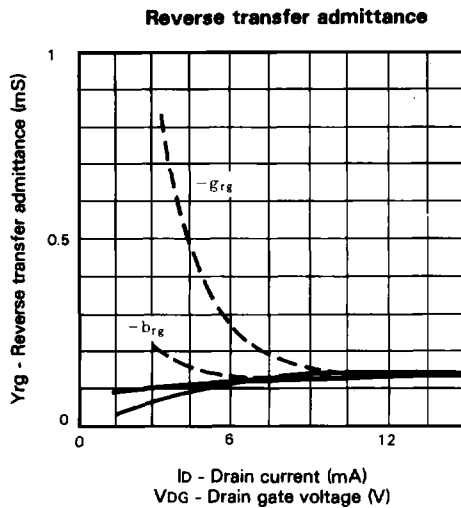
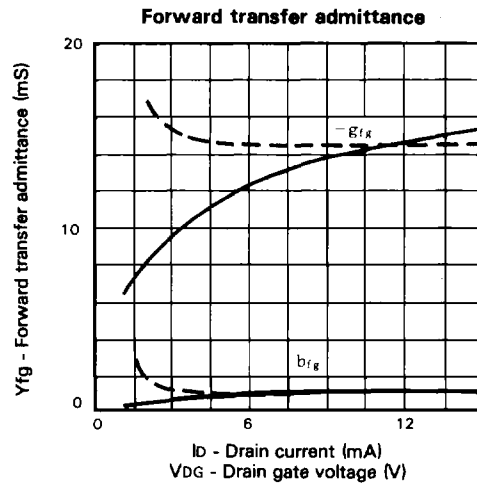
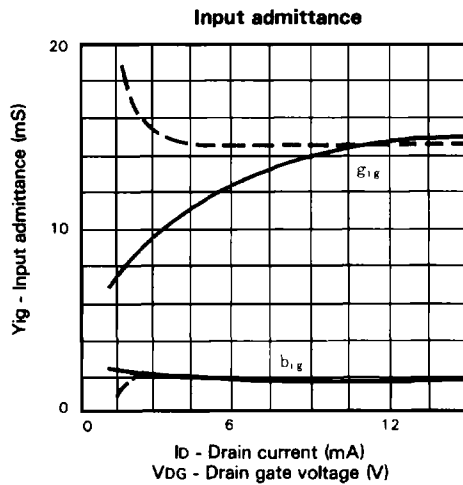


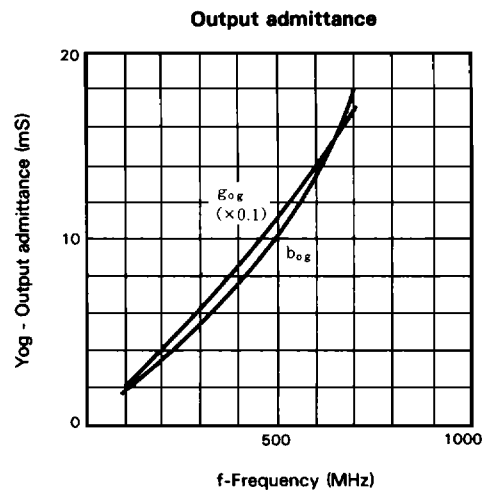
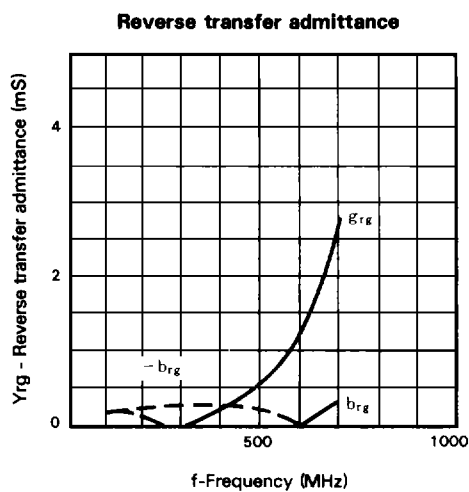
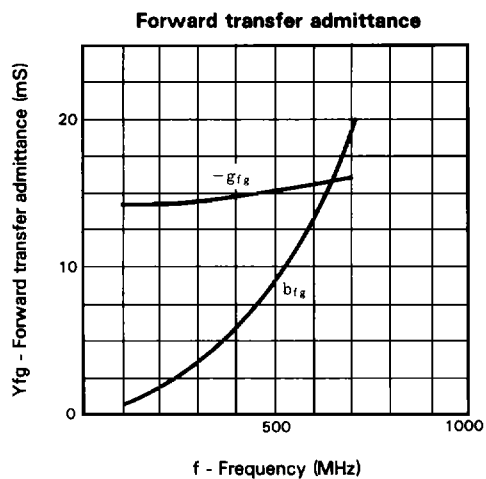
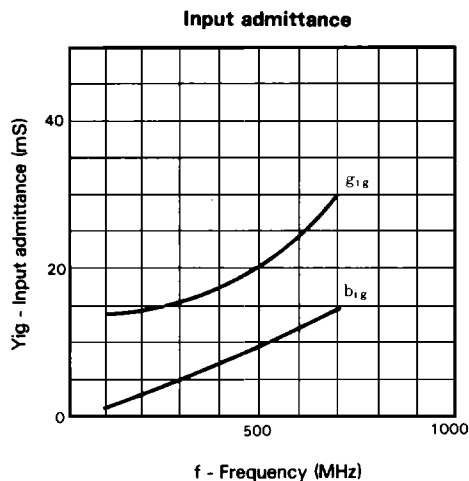
Feedback capacitance vs. Drain gate voltage

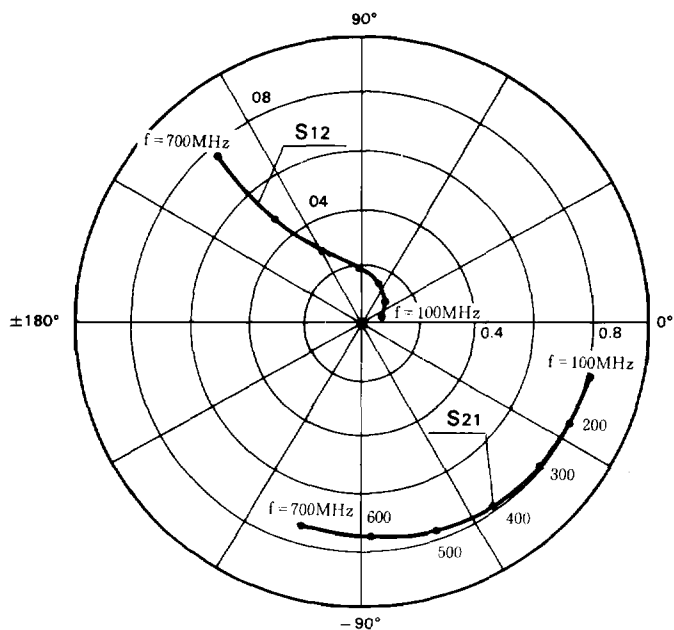
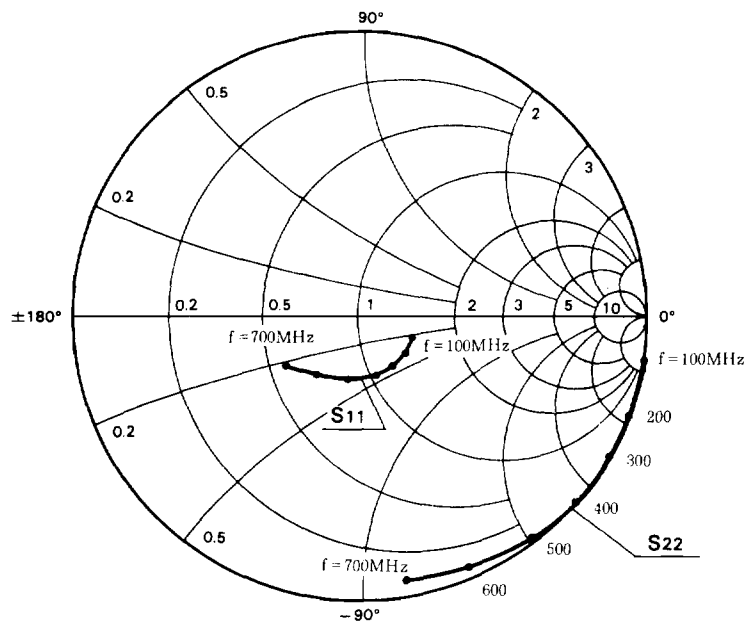
Common-gate power gain noise figure
vs. Drain current

Common Gate Y-Parameter

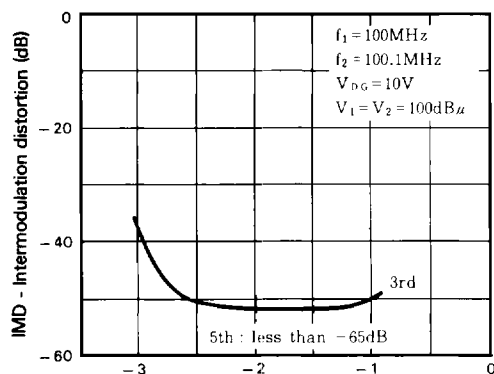
- Drain current characteristics ($V_{DG} = 10V$, $f = 100\text{ MHz}$)
 - - - Drain gate voltage characteristics ($I_D = 10\text{mA}$, $f = 100\text{ MHz}$)



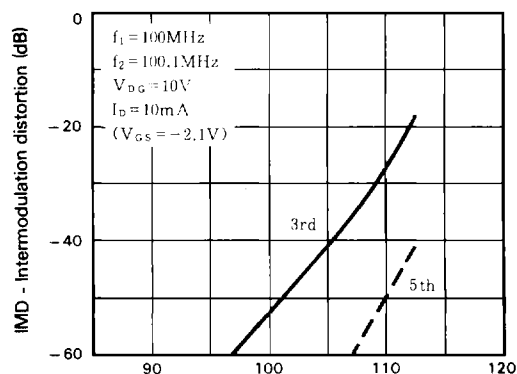
Common Gate Y-Parameter vs. Frequency ($V_{DG} = 10V$, $I_D = 10mA$)

Common Gate S-Parameter vs. Frequency ($V_{DG} = 10V$, $I_D = 10\text{ mA}$)

Intermodulation distortion characteristics

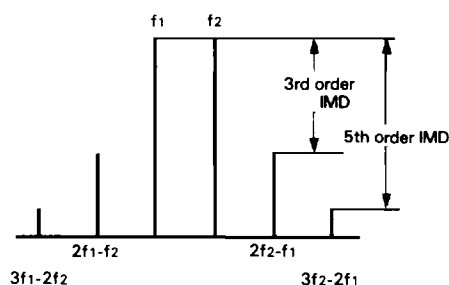
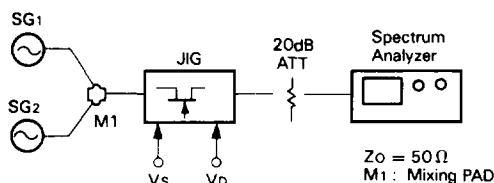


VGS - Gate source voltage (V)

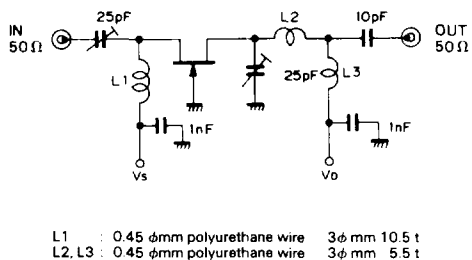


V1, V2 - Input signal level (dB μ)

Block Diagram for IMD Measurement



100 MHz IMD Test Circuit



Derating curve

